

ADI_PCN_14_0129_REV_-_Qual Report Summary

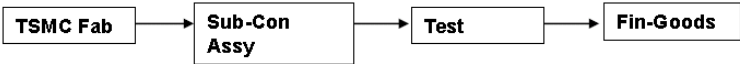
QUALIFICATION PLAN #10524			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	1*77	Passed
		1*77	Passed
Early Life Failure (ELF)	MIL-STD-883, <i>Method 1015</i>	3*667	Passed
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1*45	Passed
		1*45	Passed
Latch-Up	JEDEC <i>JESD78</i>	6	Passed
		6	Passed
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JDS-001-2011</i>	3/voltage	Passed
		3/voltage	Passed
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Passed
		3/voltage	Passed
Electrostatic Discharge <i>Machine Model</i>	JEDEC <i>JESD22-A115</i>	3/voltage	Passed
		3/voltage	Passed
Electrostatic Discharge <i>15kV IEC HBM</i>	IEC <i>6100-4-2</i>	3/voltage	Passed

*Preconditioned per JEDEC/IPC J-STD-020



**Alternate fab source for RS-232 Transceiver products.
To enable additional wafer fabrication capacity**

Current Flow:



Alternate Flow:

